Machine Learning for Biomedical Imaging Applications

Guest Editor:

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Message from the Guest Editor

Dear Colleagues,

This Special Issue aims to discuss practical applications of machine learning technologies in biomedical imaging and to enable the next generation of strong AI methods, ensuring robust and interpretable AI-based solutions. We hope that clinicians can better understand and effectively use this emerging technology, and AI researchers can further improve models and algorithms from clinical feedback.

To this end, we invite articles that bridge the gap between machine learning research and its biomedical imaging applications to be submitted and published. Research areas may include (but are not limited to) the following:

- Disease detection, disease classification, disease characterization, and disease screening;
- Treatment outcome prediction, treatment response evaluation;
- Image quality improvement, image acquisition acceleration;
- Radiation dose reduction, synthetic image generation across different modalities.

We look forward to receiving your contributions.

Special Issue

Editor-in-Chief

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Message from the Editor-in-Chief

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